

FORM PTO-1449
(REV. 7-80)
(Title Amended 3/83)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.
125397

SERIAL NO.
10/065,018

INFORMATION DISCLOSURE STATEMENT BY APPLICANT--
LIST OF ITEMS

Applicant

Marc (nmn) Schaepkens et al.

Filing Date

9/11/02

Group

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
82	AA 6 2 6 8 6 9 5	07/31/01	Affinito			
82	AB 3 9 3 2 6 9 3	01/13/76	Shaw et al.			
82	AC 5 9 9 8 8 0 3	12/07/99	Forrest et al.			
82	AD 6 0 2 3 3 7 1	02/08/00	Onitsuka et al.			
82	AE 4 5 4 0 7 6 3	09/10/85	Kirchhoff			
82	AF 5 1 8 5 3 9 1	02/09/93	Stokich, Jr.			
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	No
82	AL 0 0 2 6 9 7 3	08/27/80	EP				
82	AM 0 1 8 1 6 4 9	09/13/85	EP				
82	AN 0 1 8 2 3 3 6	04/20/00	EP				
	AO						
	AP						

OTHER INFORMATION (Including Author, Title, Date, Pertinent pages. Etc.)

82	AR	H. Suzuki et al., "Near-Ultraviolet Electroluminescence from Polysilanes 331 Thin Solid Films 64-70 (1998).
82	AS	Gijsbert Jan Meeusen, "Plasma Beam Deposition of Amorphous Hydrogenated Silicon," Thesis, University of Eindhoven, pp. 16-19 (1994).
82	AT	Bastiaan Arie Korevaar, "Integration of Expanding Thermal Plasma Deposited Hydrogenated Amorphous Silicon in Solar Cells," Thesis, University of Eindhoven, pp. 23-34 (2002).

EXAMINER

Schaepkens

DATE CONSIDERED

1/30/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	BA					
	BB					
	BC					
	BD					
	BE					
	BF					
	BG					
	BH					
	BI					
	BJ					
	BK					

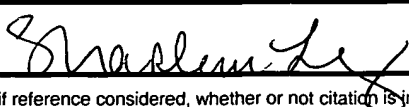
FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	No
	BL						
	BM						
	BN						
	BO						
	BP						

OTHER INFORMATION (Including Author, Title, Date, Pertinent pages. Etc.)

BR	V.J. Law et al., "RF Probe Technology for the Next Generation of Technological Plasmas," J. Phys. D: Appl. Phys., 34, 2726-2733 (2001).
BS	
BT	

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